Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/528,461	KIM ET AL.
Examiner	Art Unit
Jason M. Nolan, Ph.D.	1626

	SEARCHED		
Class	Subclass	Date	Examiner
544	131	11/13/2006	JMN
514	235.5	11/13/2006	JMN
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. INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
STN Structure Search (Registry, Caplus), printout attached	11/13/2006	JMN
ABS, Oath, Blb data, Spec, Priority Documents, & IDS reviewed	11/13/2006	JMN
Inventor Search, reviewed for double patenting	11/13/2006	JMN
East Class/Subclass searhed; printout attached	11/28/2006	JMN